

Specifications

Drawing No.	USY1M-H1-16427-00 1 / 11
Issued Date.	Apr,20,2016

Messrs: KED USA

Note: Part Number will be revised in case of specification change.

Product Type	Quartz Crystal
Series	CX2520DB
Frequency	Refer to Doc No.USY1M-H1-16427-00 Page 3/11
Customer Part Number	-
Customer Specification Number	-
KYOCERA Part Number	Refer to Doc No.USY1M-H1-16427-00 Page 3/11
Remarks Pb-Free, RoHS Compliant, MSL 1	

Customer Approval

Approval Signature	Approved Date	
	Department	
	Person in charge	

Seller

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 (Sales Division)
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 TEL. No. 075-604-3500
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Manufacturer

KYOCERA Crystal Device Corporation
 Crystal Units Division
 5850, Higashine-Koh, Higashine-Shi, Yamagata
 999-3701 Japan
 TEL. No. 0237-43-5611
 FAX. No. 0237-43-5615

Design Department	Quality Assurance	Approved by	Checked by	Issued by
KYOCERA Crystal Device Corporation Crystal Unit Application Engineering Section Crystal Units Division	S.Itoh	T.Soda	A.Muraoka	Y.Nozaki

Revision History

Rev.No.	Description of revise	Date	Approved by	Checked by	Issued by
00	First Edition	Apr,20,2016	T.Soda	A.Muraoka	Y.Nozaki

[Parts Number list]

Nominal Frequency (MHz)	KYOCERA Part Number	ESR (Ω)	Nominal Frequency Code
12.000	CX2520DB12000D0FLJC1	150	12000
13.560	CX2520DB13560D0FLJC2	150	13560
19.200	CX2520DB19200D0FLJC2	80	19200
24.000	CX2520DB24000D0FLJCC	80	24000
24.576	CX2520DB24576D0FLJC1	80	24576
25.000	CX2520DB25000D0FLJC1	60	25000
27.000	CX2520DB27000D0FLJC1	60	27000
30.000	CX2520DB30000D0FLJC1	60	30000
48.000	CX2520DB48000D0FLJC2	50	48000

1. APPLICATION

The purpose of this document is applied to CX2016DB quartz crystal.

2. KYOCERA PART NUMBER

Refer to Doc No.USY1M-H1-16427-00 Page 3/11

3. RATINGS

Items	SYMB.	Rating	Unit	Remarks
Operating Temperature range	Topr	-30~+85	deg. C	
Storage Temperature range	Tstg	-40~+85	deg. C	

4. CHARACTERISTICS

4-1 ELECTRICAL CHARACTERISTICS

Items	Electrical Specification					Test Condition	Remarks
	SYMB.	Min	Typ.	Max	Unit		
Mode of Vibration		Fundamental					
Nominal Frequency	F0		(*1)		MHz		
Nominal Temperature	T _{NOM}		+25		°C		
Load Capacitance	CL		8.0		pF		
Frequency Tolerance	df/F	-10.0		+10.0	PPM	+25±3°C	
Frequency Temperature characteristics	df/F	-15.0		+15.0		-30°C ~+85°C	
Frequency Ageing Rate		-1.0		+1.0		1 ST year	+25±3°C
Equivalent Series Resistance	ESR		(*2)		Ω		
Drive Level	Pd	0.01		100	μW		
Insulation Resistance	IR	500			MΩ	100V(DC)	

Measurement Condition

Frequency measurement

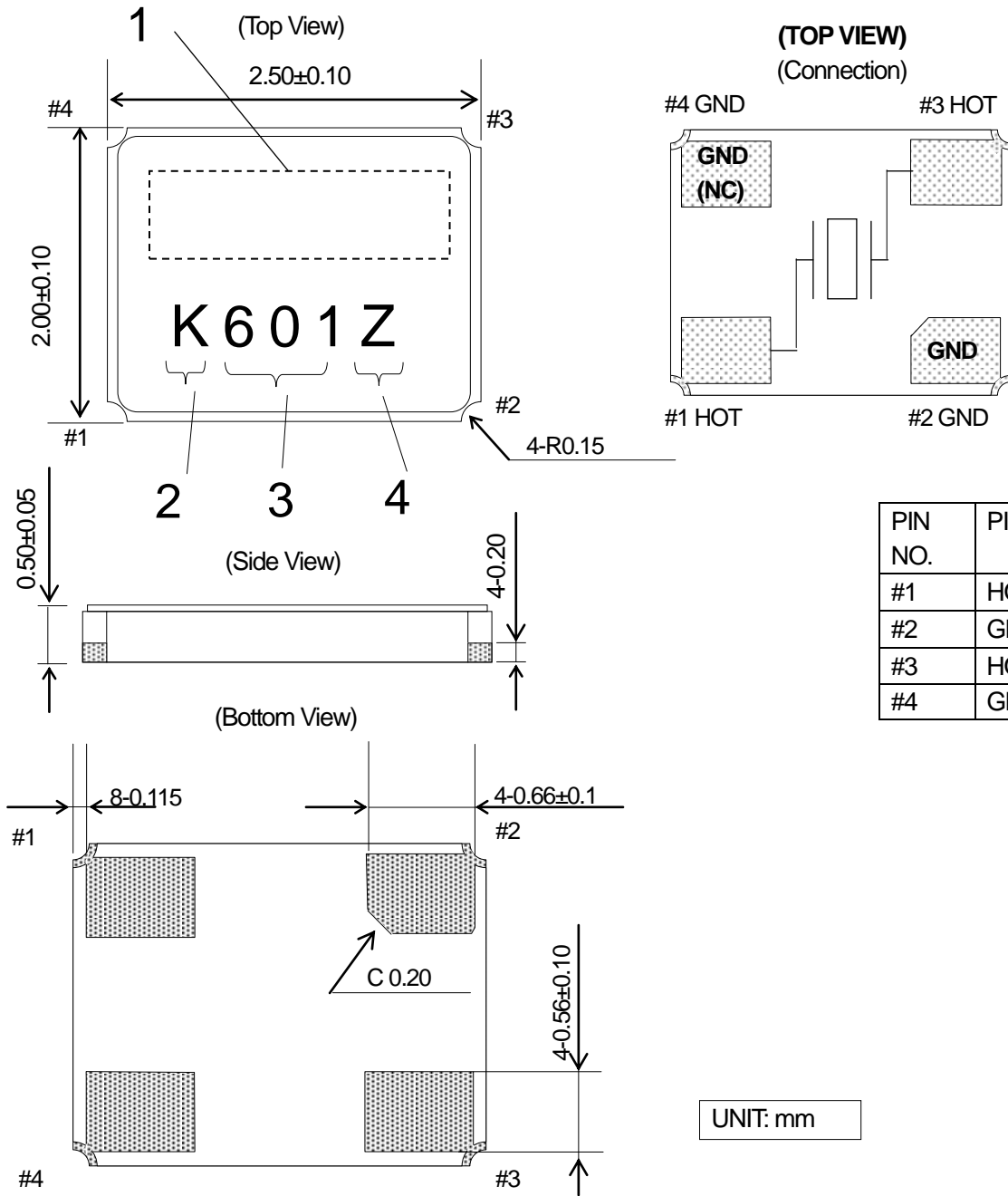
Measuring instrument : IEC PI-Network Test Fixture
IEC 60444-8 STD (Pi circuit 41901A)

Equivalent series resistance (ESR) measurement

Measuring instrument : IEC PI-Network Test Fixture
Load Capacitance : Series

*1 *2 Refer to Doc No.USY1M-H1-16427-00 Page 3/11

5. APPEARANCES, PHYSICAL DIMENSION
OUTLINE DIMENSION (not to scale)



PIN NO.	PIN Layout
#1	HOT
#2	GND
#3	HOT
#4	GND(NC)

UNIT: mm

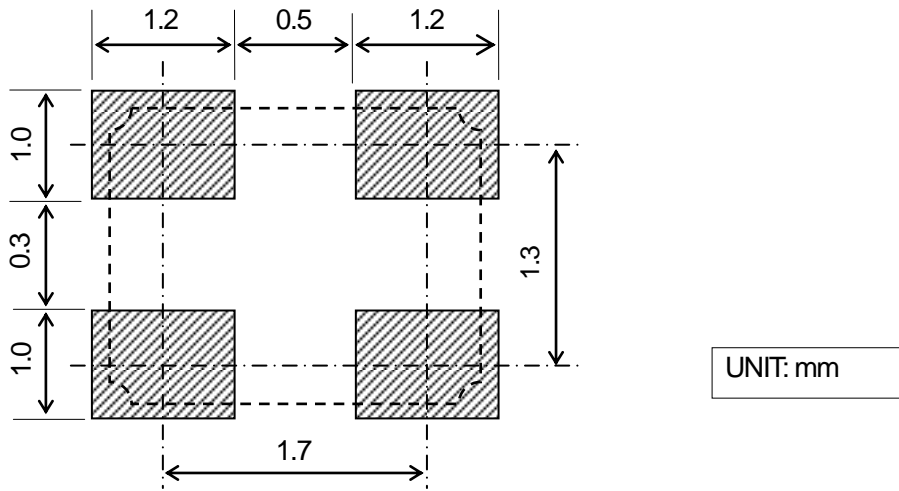
MARKING

1	Nominal Frequency	First 5digit of the frequency is indicated. *3
2	Identification	[K] is to indicate 1Pin direction.
3	Date Code	Last 1 Digit of YEAR and WEEK (Ex) 2016,Jan,01 → 601
4	Manufacturing Location	Y→Japan (Yamagata) Z→Japan (Shiga Yohkaichi) T→Thailand

*The font of marking is for reference only.

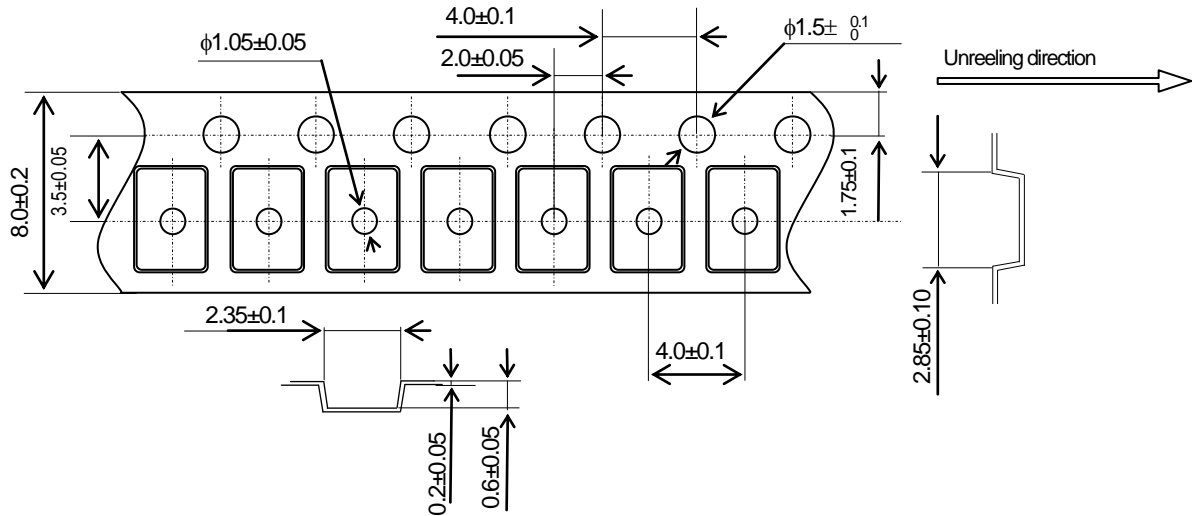
*3 Refer to Doc No.USY1M-H1-16427-00 Page 3/11

6. RECOMMENDED LAND PATTERN (not to scale)

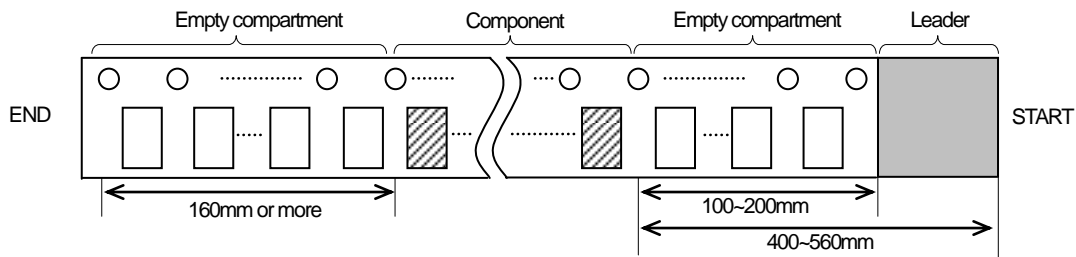


7. TAPING&REEL

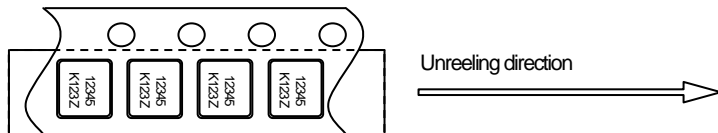
7-1.Dimensions



7-2.Leader and trailer tape

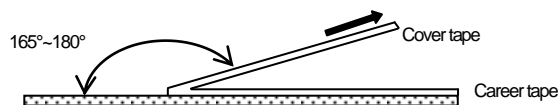


7-3.Direction(The direction shall be seen from the top cover tape side)

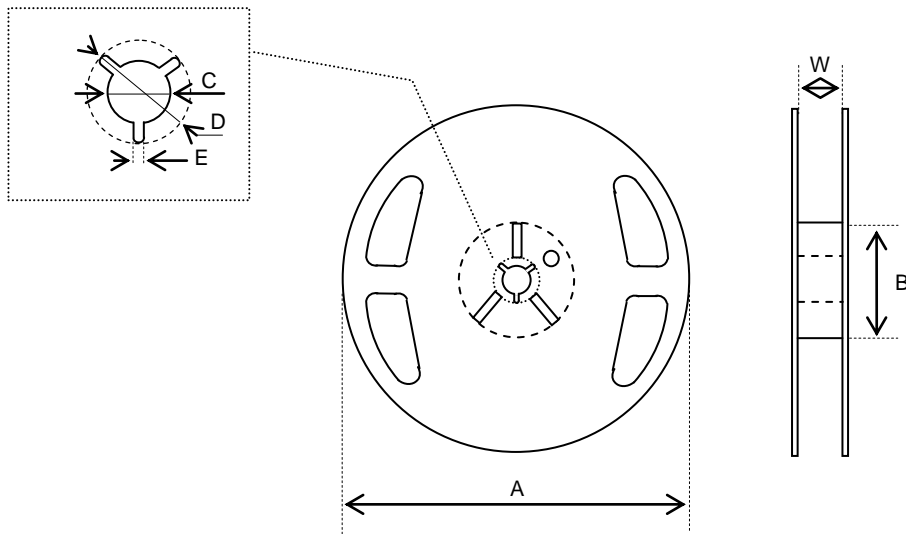


7-4.Specification

1. Material of the carrier tape is either polystyrene or A-PET (ESD).
2. Material of the cover tape is polyester (ESD).
3. The seal tape shall not cover the sprocket holes and not protrude from the carrier tape.
4. Tensile strength of carrier tape: 10N or more.
5. The R of the corner of each cavity is $0.2R_{MAX}$.
6. The alignment between centers of the cavity and sprocket hole shall be 0.05mm or less.
7. The orientation shall be checked from the top cover tape side as shown in 8-3.
8. Peeling force of cover tape: 0.1 to 1.0N .
9. The component will fall out naturally when cover tape is removed and set upside down.



7-5.Reel Specification



φ180 Reel (3,000 pcs Max.)

Symbol	A	B	C
Dimension	φ180 +0/-3	φ60 +1/-0	φ13±0.2
Symbol	D	E	W
Dimension	φ21±0.8	2.0±0.5	9±1

(Unit: mm)

φ330 Reel (12,000 pcs Max.)

Symbol	A	B	C
Dimension	φ330±2.0	φ100±1.0	φ13±0.2
Symbol	D	E	W
Dimension	φ21±0.8	2.0±0.5	9.5±0.5

(Unit: mm)

8.6 Resistance to Moisture Test condition

The quartz crystal unit shall be stored at a temperature of $+60\pm 2^{\circ}\text{C}$ with relative humidity of 90% to 95% for 240 h. Then it shall be subjected to room temperature for 1h before measurement.

8.7 Soldering condition 1.) Type of solder

Material → lead free solder paste

Melting point → $+220\pm 5^{\circ}\text{C}$

2.) Reflow temp.profile

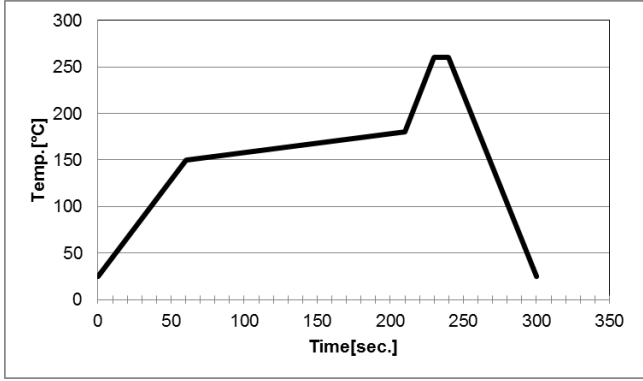
	Temp [°C]	Time[sec]
Preheating	+150 to +180	150 (typ.)
Peak	$+260\pm 5$	10 (max.)
Total	---	300 (max.)

Frequency shift : $\pm 2\text{ppm}$

3.) Hand Soldering $+350^{\circ}\text{C}$ 3 sec max

4.) Reflow Times 2 times in below Reflow temp. profile

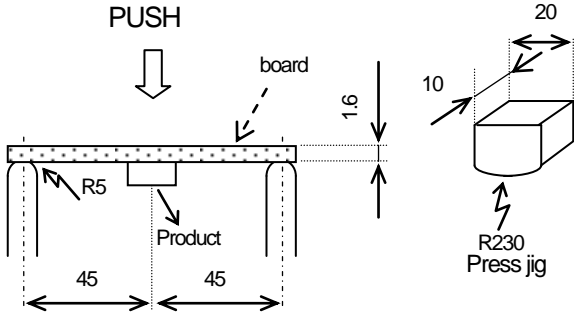
Reflow temp.profile



8.8 Bending Strength

Solder this product in center of the circuit board (40mm X 100mm), and add deflection of 3mm.

Test board : $t=1.6\text{mm}$



UNIT: mm

9. Cautions for use

(1) Soldering upon mounting

There is a possibility to influence product characteristics when Solder paste or conductive glue comes in contact with product lid or surface.

(2) When using mounting machine

Please minimize the shock when using mounting machine to avoid any excess stress to the product.

(3) Conformity of a circuit

We strongly recommend to make sure that Negative resistance (Gain) of IC is designed to be 5 times the ESR (Equivalent Series Resistance) of crystal unit.

10. Storage conditions

Please store product in below conditions, and use within 6 months.

Temperature +18 to +30°C, and Humidity of 20 to 70 % in the packaging condition.

11. Manufacturing location

Kyocera Crystal Device Corporation Yamagata Plant

Kyocera Crystal Device Corporation Shiga Yohkaichi Plant

Kyocera Crystal Device (Thailand) Co., Ltd

12. Quality Assurance

To be guaranteed by Kyocera Crystal Device Quality Assurance Division

13. Quality guarantee

In case when Kyocera Crystal Device Corporation rooted failure occurred within 1 year after its delivery, substitute product will be arranged based on discussion. Quality guarantee of product after 1 year of its delivery is waived.

14. Others

In case of any questions or opinions regarding the Specification, please have it in written manner within 45 days after issued date.